# **IOWA STATE UNIVERSITY Digital Repository**

[Retrospective Theses and Dissertations](https://lib.dr.iastate.edu/rtd?utm_source=lib.dr.iastate.edu%2Frtd%2F15358&utm_medium=PDF&utm_campaign=PDFCoverPages)

[Iowa State University Capstones, Theses and](https://lib.dr.iastate.edu/theses?utm_source=lib.dr.iastate.edu%2Frtd%2F15358&utm_medium=PDF&utm_campaign=PDFCoverPages) **[Dissertations](https://lib.dr.iastate.edu/theses?utm_source=lib.dr.iastate.edu%2Frtd%2F15358&utm_medium=PDF&utm_campaign=PDFCoverPages)** 

2008

# Nonlinear device characterization and second harmonic impedance tuning to achieve peak performance for a SiC power MESFET device at  $2$ GHz

Saalini Valli Sekar *Iowa State University*

Follow this and additional works at: [https://lib.dr.iastate.edu/rtd](https://lib.dr.iastate.edu/rtd?utm_source=lib.dr.iastate.edu%2Frtd%2F15358&utm_medium=PDF&utm_campaign=PDFCoverPages) **Part of the [Electrical and Electronics Commons](http://network.bepress.com/hgg/discipline/270?utm_source=lib.dr.iastate.edu%2Frtd%2F15358&utm_medium=PDF&utm_campaign=PDFCoverPages)** 

#### Recommended Citation

Sekar, Saalini Valli, "Nonlinear device characterization and second harmonic impedance tuning to achieve peak performance for a SiC power MESFET device at 2GHz" (2008). *Retrospective Theses and Dissertations*. 15358. [https://lib.dr.iastate.edu/rtd/15358](https://lib.dr.iastate.edu/rtd/15358?utm_source=lib.dr.iastate.edu%2Frtd%2F15358&utm_medium=PDF&utm_campaign=PDFCoverPages)

This Thesis is brought to you for free and open access by the Iowa State University Capstones, Theses and Dissertations at Iowa State University Digital Repository. It has been accepted for inclusion in Retrospective Theses and Dissertations by an authorized administrator of Iowa State University Digital Repository. For more information, please contact [digirep@iastate.edu](mailto:digirep@iastate.edu).



#### Nonlinear device characterization and second harmonic impedance tuning to achieve peak performance for a SiC power MESFET device at 2GHz

by

#### Saalini Valli Sekar

#### A thesis submitted to the graduate faculty

in partial fulfillment of the requirements for the degree of

#### MASTER OF SCIENCE

Major: Electrical Engineering

Program of Study Committee: Robert J. Weber, Major Professor Mani Mina Akilesh Tyagi

Iowa State University

Ames, Iowa

2008

Copyright © Saalini Valli Sekar, 2008. All rights reserved.



www.manaraa.com

#### **UMI Number: 1453894**

Copyright 2008 by Sekar, Saalini Valli

All rights reserved

#### **INFORMATION TO USERS**

The quality of this reproduction is dependent upon the quality of the copy submitted. Broken or indistinct print, colored or poor quality illustrations and photographs, print bleed-through, substandard margins, and improper alignment can adversely affect reproduction.

In the unlikely event that the author did not send a complete manuscript and there are missing pages, these will be noted. Also, if unauthorized copyright material had to be removed, a note will indicate the deletion.

# UMI

UMI Microform 1453894 Copyright 2008 by ProQuest LLC<br>All rights reserved. This microform edition is protected against unauthorized copying under Title 17, United States Code.

> **ProQuest LLC** 789 East Eisenhower Parkway P.O. Box 1346 Ann Arbor, MI 48106-1346

## **TABLE OF CONTENTS**









## LIST OF FIGURES





# LIST OF TABLES





#### **ABSTRACT**

This thesis presents a way to make nonlinear device measurements for a power MESFET device using the load pull system. The device was characterized at the fundamental and second harmonic frequencies during large signal operation. The data thus collected was used in designing the input and output impedance matching networks that would optimize the performance of the device. A power MESFET device like the one used to conduct this experiment is mainly used in designing power amplifiers for communication systems including the transmitters used in satellites. Therefore efficiency of the part is of the utmost importance. By characterizing the device and utilizing matching impedance networks on the input and the output of the device, the efficiency of the device can be greatly improved. The characterization of the device, the construction of the matching networks, simulation and test results for the output power are all presented in this thesis.



www.manaraa.com

#### CHAPTER 1. OVERVIEW

Load pull is an automated measurement technique used to make measurements on a device under test (DUT) while under operating conditions. This is a very important measurement technique utilized for large signal, non linear devices [1]. Device characterization by load pull is a means of identifying the conditions, by measurement, under which the device has the optimum performance. By characterizing the device, optimal circuits can be designed to operate under conditions that result in maximum performance. Characterizing a non linear device is particularly difficult because the absence of linearity means that the relationships between the device terminals are no longer simple [2]. In the case of linear devices, characterization is not a problem because the small signal Sparameters can usually be used to predict the performance at various loads. Several methods have been proposed for characterizing non-linear devices. The load pull is one such technique that allows the user to characterize a large signal, non-linear device while under operation [1].

#### 1.1 Introduction to Load Pull

Load pull consists of changing the load impedance seen by the DUT and measuring the device operation simultaneously. This technique is called load pull because the load impedance is varied or "pulled" using a load tuner. Similarly, the source impedance can also be varied using a source tuner when making measurements of the device performance. This is called source pull [1]. Load pull and source pull are often used to characterize microwave and RF power devices. The device itself is characterized with respect to the input source impedance and output load impedance using the corresponding automated tuner since impedance is a parameter that relates to voltage, current and power. Devices can be characterized with respect to impedance for noise figure, gain, output power, efficiency, linearity, etc [3].

#### 1.2 Problem Statement

SiC rf power devices capable of operating at temperatures in the 200˚C range have recently become available. The main objective of this research project was to characterize



these new devices for best performance. The DUT that was used is the CREE CRF24010F. This is a 10 W, unmatched silicon carbide (SiC) RF power Metal Semiconductor Field-Effect Transistor (MESFET). This device has various applications including a wide range of uses in the field of communications. It can also be used in the design of class A, A/B power amplifiers, CDMA, TDMA, EDGE, broadband amplifiers, etc [4]. Looking at the areas of application for this device, it is clear that the output power and efficiency of the device are critical performance parameters of this device. Therefore characterizing the device for maximum output power will significantly improve device performance. The measurements for this device were made at a fundamental frequency of 2GHz using harmonic load pull at 4GHz.

#### 1.3 Approach

The approach taken to improve the device circuit performance was to tune the input and output impedance for the best match. This improves the device performance. Since the particular SiC MESFET device that is used in this project is a square law device, the device generates second harmonics. Therefore, in addition to characterizing the DUT at the fundamental frequency with respect to impedance, the DUT can also be characterized at the harmonic frequencies with respect to impedance as well. The device's circuit performance can further be optimized by characterizing the device at the second and third harmonic frequencies with respect to impedance. In recent years, harmonic load and source pull has been gaining in popularity [5]. Harmonic load pull can be important in optimizing the efficiency and linearity of the device where as harmonic source pull can be important in optimizing the device performance by controlling the amount of harmonic generation. Harmonic source pull is just as important as harmonic load pull, especially in cases where performance is critical [5].

#### 1.4 Overview of the device characterization procedure

The device used in the study was first measured for output power at the fundamental frequency of 2GHz using the load pull technique. By setting the load and source tuner at the optimum load and source impedances, the maximum output power for the device along with the efficiency for the device was measured and recorded. The setup was then changed to



include harmonic source pull as well. The additional second harmonic tuner was adjusted for an optimum impedance along with the load and source tuners. After an optimum harmonic termination was achieved, the input matching network and the output matching network corresponding to the established optimum tuner positions was measured. These measurements are then used to construct input and output matching networks for the device using standard rf and microwave circuit synthesis techniques. The same device is then connected to the optimum input and output matching network that was constructed in order to verify that the device produces the same output power as measured with load and source tuners. The setup, measurement techniques, results and an analysis of the results will be presented in later sections of this thesis.

#### 1.5 Literature Review

 During the process of searching for publications in this area, something that was noticeable was the fact that research using load and source pull measurement techniques is limited. Even though these types of measurements are gaining more popularity in recent years, there is still a lot of progress that can be made. From my experience working with the load pull setup, this is an underutilized technique. As the need for RF circuits increases in the future, the research using the load pull measurement technique should also increase.

 One of the major uses of load pull measurement techniques is in designing power amplifiers. When designing a power amplifier used in communication circuits, efficiency is a very important parameter to consider. High efficiency requires large signal operation of the device. The advantage of using a load pull technique is that the device can be measured under actual large signal operating conditions. Load pull measurements are often used in making measurements to determine the matching impedances that are needed for optimum power amplifier design. These matching networks are then created and connected to the input and output of the DUT to extract the best performance of the DUT. Usually the matching impedance is measured and synthesized at the fundamental frequency, but matching impedances at the harmonic frequencies often improves the performance of the device significantly [6]. One of the papers that was reviewed, [6], uses a BJT as the DUT to make



output power and efficiency measurements before and after load pull, utilizing matching networks at the fundamental and second harmonic frequencies.



#### CHAPTER 2. SETUP

load and source pull measurement techniques require a very elaborate setup. This includes automated tuners for the load and source impedance, signal generators, power supplies, a high isolation switch, power meter, oscilloscope, spectrum analyzer, etc. Two different types of setups were used when characterizing the DUT used in this study. The first one was a setup used to make output power measurements after tuning the source and load tuners for optimum impedances over a range of frequencies including the fundamental frequency of 2GHz. The other setup was the second harmonic source pull setup that allows the load, source and the second harmonic tuners to be set to optimum impedances. The two setups are similar, but with significant differences between them. In this chapter, the techniques that were used to make these measurements as well as the different components of the load pull setup for the two different configurations are described. An overall picture of the setup is shown in Appendix 1.

#### 2.1 Measurement Technique

The load pull system that was used for the power and harmonic measurements utilized pulsed bias and pulsed RF signals. The pulsed bias and pulsed RF signals were used in order to minimize the risk of DUT burn out and to limit the temperature rise of the MESFET die. The pulsed signals are turned on for 10µs and turned off for 1ms. The measurements were made when the pulsed bias and RF signals were "on." On the load pull system, the pulsed bias and pulsed RF signals were achieved using a custom built pulse generator and high isolation switch as shown in Fig 1 and Fig 2 [7].

#### 2.2 Instrument Setup

Load pull and source pull measurements were made using an automated tuner setup to do the measurements. The automated tuner system (ATS) had been purchased from Maury Microwave Systems. This system consists of a tuner controller, two tuners and software to control these instruments. The software that is provided with this initial setup is called SNPW. The different setups require different configurations, but the instruments that were used were all the same. A general purpose interface bus (GPIB) is used to communicate between the instruments and the SNPW software. Some of the instruments and their GPIB



addresses that were used for making these automated measurements are as shown in Table 1.

| <b>Instrument Type</b>    | <b>Model Number</b> | <b>GPIB</b><br><b>Address</b> |
|---------------------------|---------------------|-------------------------------|
| Tuner Controller          | MT986B02            |                               |
| Network Analyzer          | W37300              |                               |
| <b>Output Power Meter</b> | <b>HP4418A</b>      | 13                            |
| <b>RF Power Source</b>    | <b>HP8648C</b>      | 19                            |
| Spectrum Analyzer         | <b>HP8560A</b>      | 20                            |
| <b>GPIB Board</b>         | <b>PCI-GPIB</b>     |                               |

Table 1: Instruments used in the load and source pull measurements

In addition to these instruments, a few power supplies were used to set the bias for the device as well. These instruments were used in both the initial load pull measurements as well as the harmonic source pull measurements.

#### 2.3 Biasing the Device

The SiC MESFET that was characterized is a depletion mode part. In depletion mode parts, the gate bias that is applied is negative. The negative voltage at the gate will repel electrons (because of their negative charge) away from the gate. This creates a depletion region around the gate region because electrons are the majority current carriers in n-type silicon. By depleting the gate region, the size of the channel is reduced and the current flow is also reduced. Increasing the negative gate voltage decreases the channel size which in turn decreases drain current flow. Decreasing the negative gate voltage increases the channel size which in turn increases drain current flow. The bias conditions used for the DUT used in this study are shown in Fig 1.



Figure 1: DUT - Depletion mode SiC MESFET device biasing



During the measurements the drain to source voltage was biased at 25V and the drain current was biased to be 530 mA. The gate voltage was adjustable such that it varied over several milli-volts in order to satisfy the drain current setting of 530 mA. The average gate voltage for the DUT used was around -8V. A measured I-V curve for the device is shown in Fig 2.

7



#### V-I curves for CRF24010F

Figure 2: Measured I-V curves for the DUT (pulse operation, 10us, 1% duty cycle)

#### 2.4 Initial load pull Measurement Setup

For the initial load pull measurements, the system was setup to measure output power and efficiency of the MESFET. The setup used to do these measurements is shown in Fig 3.





Figure 3: Load pull setup for measuring output power

The device was placed in a 5 ohm fixture customized for this particular device. On the input gate side, the fixture was connected to a male-to male connector followed by a coupler which was connected to a male-to-male connector before it was connected to the source tuner. On the output drain side, the fixture was connected to a male-to-male connector, then to a coupler that is in turn connected to a load tuner. The source tuner and load tuner were connected to a tuner controller. The tuner controller itself was connected to the computer through GPIB cables. The SNPW software was used to control the tuner position of the load and source tuners. The input bias tee used to apply gate bias to the DUT was connected to the input of the source tuner and the output bias tee used to apply the drain bias on the device was connected to the load tuner output. The high isolation switch and the custom built pulse generator seen in Fig 3 were used to generate the pulsed signal for the bias and RF signals as described in Section 2.1. The 1W and 2W amplifiers on the gate of the device were used to increase the input power available. Sufficient power available at the input of the device was necessary to produce high output power, which was the major objective for the device characterization. On the output drain side, the output power is



measured using a power sensor that was in turn connected to an output power meter where the power was displayed [7]. The power that is displayed on the output power meter is not the true output power because of losses in the system; these losses need to be accounted for as well. Using a one percent duty factor results in an effective 20 dBm of power loss when using pulsed bias and rf signals and there is another 20 dBm attenuator used in the output system setup. These losses were accounted for by adding 40 dBm to whatever the power meter reads. This allows the true power out at the drain terminal of the DUT to be computed after the de-embedding is complete. The 40 dBm power loss was accounted for by adding this to the output power meter display if the load pull measurements were done manually. If the automated SNPW software was used, then losses were automatically accounted for in the output that the software displayed. This is because the system is configured and each and every device that is added to the system (any device that is not the DUT but is still part of the test system setup) is accounted for by initially characterizing the device and integrating the Sparameter file for the device in the workbench of the SNPW software when initializing the system.



Figure 4: Second harmonic source pull measurement setup



#### 2.5 Second harmonic source pull measurement setup

The setup for the second harmonic source pull measurements was very similar to the initial load and source pull measurement setup from Fig 3. Fig 4 shows the slightly modified setup used to make second harmonic source pull measurements.

There is very little difference between the initial setup used to measure output power, gain and efficiency and the setup used to make second harmonic source pull measurements. The major difference is in the addition of a diplexer and a second harmonic tuner. The diplexer was used to separate the diplexer signal path at the fundamental frequency of 2 GHz and the second harmonic frequency of 4 GHz. The diplexer design is discussed in section 3.2.1 in more detail. The second harmonic tuner was connected to the 4GHz port of the diplexer and the other end of the tuner was terminated with a high power 50 Ohm termination [5]. The output power meter from the initial setup was replaced with a spectrum analyzer so than the power at 2 GHz and 4 GHz can be measured separately.



#### CHAPTER 3. DESIGN AND MEASUREMENTS

This section explains in detail the procedure and techniques used in making the load and source pull measurements. It also describes the design of the diplexer and matching networks that were utilized in the second harmonic source pull measurements.

#### 3.1 Fundamental frequency load pull measurement

Each tuner position corresponds to certain impedance. The tuner positions set the input and output impedances of the DUT. By changing the tuner positions either manually or automatically using the SNPW software, the input or output impedances was changed and set at the optimal position that provided the maximum output power. The load pull was run with the source tuner set at the optimum source impedance position. The results obtained from these measurements correspond to the output power at various tuner positions that in turn corresponds to various load impedances for a set frequency and bias condition. By running a load pull using constant optimum source impedance, the varying output power results corresponding to various load impedances were displayed as contours on a Smith Chart®. The point that corresponds to the maximum output power was considered the optimum load impedance. Therefore, the optimum source and load impedance for the device at a certain frequency and bias condition was obtained automatically minimizing tedious, long and tiresome manual data collection [7].

#### 3.1.1 Measured Results

 Initially, the second harmonic content of the signal was not taken into consideration. The CREE CRF24010F device's output power measurements were obtained at a range of fundamental frequencies to look at the device operation and the device capabilities. The range of frequencies chosen was from 1.8 GHz to 3.0 GHz. All measurements were made with the device bias set at Vds = 25V, Ids = 530mA and Vgs  $\approx$  -8V. At each of the frequencies chosen, the device was biased at the set conditions, and the optimum source impedance was found. This was set by manually changing the source tuner until the maximum optimum power was achieved. The impedance corresponding to the tuner position that achieved maximum output power is recorded as the optimum source impedance. With



the source tuner fixed at this optimum impedance position, the load tuner was varied using the automated SNPW program and the results thus obtained for output power, efficiency and gain were plotted on a Smith Chart to show the load circles. The optimum load impedance for the device was also found by looking at the results and finding the load impedance that provided the maximum output power and efficiency. The optimum source and load impedances that were thus obtained are tabulated and shown in Table 2. The optimum source impedance and load impedance circles are also shown in Fig 5 [8]. The load pull circles that were obtained from the automated SNPW program for a fundamental frequency of 2.0GHz are included in Appendix 2.

| Frequency | <b>Source Impedance</b><br>$(\Omega)$ |           | <b>Load Impedance</b><br>$(\Omega)$ |           |
|-----------|---------------------------------------|-----------|-------------------------------------|-----------|
| (GHz)     | Real                                  | Imaginary | Real                                | Imaginary |
| 1.8       | 3.69                                  | 2.92      | 3.1                                 | 9.63      |
| 1.9       | 4.69                                  | 3.6       | 2.63                                | 8.57      |
| 2         | 2.33                                  | 2.78      | 3.79                                | 6.37      |
| 2.1       | 2.1                                   | 1.32      | 3.3                                 | 6.36      |
| 2.2       | 2                                     | 1.86      | 3.15                                | 3.02      |
| 2.3       | 2.62                                  | $-0.19$   | 2.07                                | 3.58      |
| 2.4       | 2.94                                  | 0.48      | 1.77                                | 1.93      |
| 2.5       | 2.71                                  | $-0.56$   | 1.42                                | 0.6       |
| 2.6       | 3.82                                  | $-2.25$   | 1.19                                | 1.46      |
| 2.7       | 5.2                                   | $-2.35$   | 2.98                                | $-0.02$   |
| 2.8       | 4.04                                  | $-2.33$   | 4.9                                 | 0.28      |
| 2.9       | 3.92                                  | $-3.36$   | 3.74                                | $-2.28$   |
| 3         | 4.83                                  | $-3.56$   | 4.63                                | $-5.49$   |

Table 2: Optimum load and source impedances of the DUT at Vdd=25V and Ids=530mA







Figure 5: Optimum load impedances for DUT (left chart) , Optimum source impedances for DUT (right chart)

When making load-pull measurements, a new problem was noticed. When certain impedances on the load circle were chosen, the drain current changed from the original setting, thus making the data recorded useless. Since the bias was set to  $Id = 530 \text{mA}$ , any dramatic change in the bias would disrupt a proper load pull measurement as load circles are supposed to have the same bias along the contours. Since the input drive of the device is changed within a pre-set range during load pull, the bias change problem was investigated further by exploring the relationship between input drive and the drain current. The following sections will include measured data as well as simulated data of the relationship between input drive and drain current. It also includes a theoretical analysis and a description of a possible reason for this condition.

#### 3.1.1.1 Relationship between input drive and drain current – Measured Data

Since the drain current of the MESFET was observed to change when the input drive was changed, the relationship between these two variables was further investigated. The drain current was measured as a function of input power for the device at 2.0 GHz with the load and source tuners set at the optimum load and source impedance positions. Multiple measurements were made to verify the trend. Measurements were made by first turning off the input power and adjusting the Vgs value to obtain an Ids current of 150mA, 200mA and 300mA at dc and then gradually changing the input power and recording the corresponding Ids values while Vgs was held constant. The data thus obtained is shown in Fig 6.





Figure 6: Measured input drive vs. drain current relationship at 2.0GHz

#### 3.1.1.2 Relationship between input drive and drain current – Simulated Data

A model of the SiC MESFET device was used to obtain simulated results. Simulation was done to verify that the measured data matched the simulation results. The result from the simulation is shown in Fig 7. This curve matches the trend of the measured results shown in Fig 6.



Figure 7: Simulated input drive vs. drain current relationship at 2.0GHz



Fig 8, depicts the I-V curves that were simulated using a device model and the I-V curves that were measured under pulse operation for the MESFET device. With the exception of a slight difference in the threshold voltage, the measured and simulated values are a close match. The difference seen at higher voltages may be due to the device's temperature rise difference between CW and pulse operation.



Figure 8: Measured and simulated I-V curves for the DUT

#### 3.1.1.3 Relationship between input drive and drain current – Theoretical Analysis

A theoretical analysis was also done to confirm that trends seen in the measured and simulated data for the input power vs. drain current relationship have a theoretical basis. Using the approximate MESFET equations [9],

$$
I_{DS} = K(V_{GS} + V_T)^2 \tag{1}
$$

where,

$$
K = \frac{I_p}{V_p^2} \quad \text{and,} \tag{2}
$$

$$
V_T = V_p + V_{B1} \tag{3}
$$

In these equations,



Ip is the pinch-off current,

Vp is the pinch-off voltage, and

 $V_{B1}$  is the built-in gate voltage.

Substituting and simplifying these equations results in,

$$
I_{DS} = K(V_{GS} + (V_p + V_{B1}))^2
$$
 (4)

In the high input power situation,  $V_{GS}$  can be written as,

$$
V_{GS} = A\cos(\omega t) + V_{gso} \tag{5}
$$

Substituting (5) into (4) gives,

$$
I_{DS} = K((A\cos(\omega t) + V_{\rm gso}) + (V_p + V_{B1}))^2
$$
\n(6)

$$
I_{DS} = K((A\cos(\omega t)) + (V_{gso} + V_p + V_{B1}))^2
$$
\n(7)

Assume that

المشارات

 $C = V_{gso} + V_p + V_{B1}$ (8)

then (7) can be re-written as,

$$
I_{DS} = K((A\cos(\omega t)) + C)^2
$$
\n(9)

Expanding (9) results in,

$$
I_{DS} = K[(A^{2}\cos^{2}(\omega t)) + 2(A\cos(\omega t))(C) + C^{2}]
$$
\n(10)

$$
I_{DS} = K \left[ \left( \frac{A^2}{2} + \frac{A^2 \cos(2\omega t)}{2} \right) + 2AC \left( \cos(\omega t) \right) + C^2 \right]
$$
\n(11)

Where C is given by (8) and  $C^2$  is given by (12) below:

$$
C^{2} = V_{gso}^{2} + V_{p}^{2} + V_{B1}^{2} + 2 V_{gso} V_{p} + 2 V_{gso} V_{B1} + 2 V_{p} V_{B1}
$$
\n(12)

Substituting (8) and (12) back into (11) results in

$$
I_{DS} = K \left[ \frac{A^2}{2} + \frac{A^2 \cos(2\omega t)}{2} + \left( 2A V_{gso} + 2A V_p + 2A V_{B1} \right) \cos(\omega t) + V_{gso}^2 + V_p^2 + V_{B1}^2 + 2V_{gso} V_p + 2V_{gso} V_{B1} + 2V_p V_{B1} \right]
$$
\n(13)

$$
I_{DS-dc} = K \left[ \frac{A^2}{2} + V_{gso}^2 + V_p^2 + V_{B1}^2 + 2 V_{gso} V_p + 2 V_{gso} V_{B1} + 2 V_p V_{B1} \right]
$$
(14)

When 
$$
\frac{A^2}{2} >> C
$$
,  $I_{DS-dc} = K \frac{A^2}{2}$  (15)

#### www.manaraa.com

Looking at (13), at dc, the amplitude of the input sinusoidal signal has a significant effect on the drain current. This dc offset caused by the input signal is one reason for the changes in the drain current and therefore causes changes in the drain bias current during load pull measurements. The relationship portrayed by (15) does not perfectly match the simulated and measured results.

The initial theory was that the Ids equation used to do this analysis is a simple representation of the actual model. In reality there are other variables that may influence the relationship between drain current and the input drive.

A more complex and accurate model will depict this relationship better. Further analysis was done and (1) was replaced with a drain current equation that included the early voltage effect and the derivation was repeated to see the changes in this relationship. Fig 9 shows a general Ids vs. Vds relationship for a MESFET. In this figure, the early voltage is depicted using the variable  $V_A$ . This figure is mainly used to show the variables used when deriving the Ids equation [10].



Figure 9: I-V curves for the DUT displaying variables used in theoretical analysis

Using this figure and after careful derivation, the Ids equation that was arrived at is shown in (16)

$$
I_{DS} = \left(\frac{\hat{I}_{dss}}{V_{DC} - V_A} \frac{(V_g - V_T)^2}{V_T^2} \frac{V_A}{I_{do}} + 1 - \frac{V_{DC}}{I_{do}R}}{\frac{1}{V_{DC} - V_A} \frac{(V_g - V_T)^2}{V_T^2} R + 1} + \frac{V_{DC}}{R} + I_{do}\right)
$$
(16)

The input signal can be estimated to be similar to (17) below.



$$
V_g = V_{go} + A \cos(\omega t) \tag{17}
$$

$$
V_g - V_T = V_{go} - V_T + A\cos(\omega t) \tag{18}
$$

$$
\left(V_{g} - V_{T}\right)^{2} = \left(V_{g0} - V_{T}\right)^{2} + 2A\cos(\omega t)\left(V_{g0} - V_{T}\right) + A^{2}\cos^{2}(\omega t)
$$
\n(19)

$$
= (V_{g0} - V_T)^2 + 2A\cos(\omega t)\left(V_{g0} - V_T\right) + \frac{A^2}{2} + \frac{A^2\cos(2\omega t)}{2}
$$
\n(20)

Substituting (20) into (16) and looking at the dc value, (21) can be obtained.

$$
I_{DS-dc} = \left(\frac{W + XA^2}{Y + ZA^2}\right) + K\tag{21}
$$

where,

$$
W = \frac{\hat{I}_{ds} V_A (V_{go} - V_T)^2}{(V_{DC} - V_A) I_{do} V_T^2} + \frac{V_{DC}}{I_{do} R} + 1
$$
\n(22)

$$
X = \frac{\hat{I}_{dss} V_A}{2(V_{DC} - V_A) I_{do} V_T^2}
$$
 (23)

$$
Y = -\frac{\hat{I}_{ds}R(V_{go} - V_T)^2}{(V_{DC} - V_A)V_T^2} + 1
$$
\n(24)

$$
Z = -\frac{\hat{I}_{dss}R}{2(V_{DC} - V_A)V_T^2}
$$
(25)

$$
K = \frac{V_{DC}}{R} + I_{do} \tag{26}
$$

The relationship shown in (21) still does not perfectly match the trends from the simulation and measurements. However, when performing this analysis, it was discovered that the assumptions made about the MESFET in Fig 9 did not match the actual results. In Fig 9, it is assumed that the early voltage,  $V_A$ , is constant voltage that does not have any relationship to Vgs. However, when examining the simulation and measured results, this is not the case. The early voltage changed as a function of Vgs. The analysis performed using (16)-(26) needs to take this relationship into account as well. This will have a definite impact on the final Ids vs A relationship shown in (21). Once the relationship between the two variables is determined, a more accurate theoretical analysis of drain current vs. input drive could be obtained.





Figure 10: 8-pole diplexer schematic



#### 3.2 Second harmonic source pull measurement

The main goal of this research project was to increase the device circuit performance. This is mainly done through impedance tuning at the fundamental frequency and constructing a matching network using the optimum impedances. Some investigators have discovered that second harmonic tuning also has a significant impact on the performance of the device [5]. Therefore, a process similar to the fundamental frequency impedance tuning was adapted for the second harmonic tuning as well. The diplexer in the setup separates the fundamental and second harmonic frequencies. The fundamental frequency port of the diplexer is connected to the fundamental impedance tuner whereas the second harmonic frequency port of the diplexer is connected to the second harmonic impedance tuner. Before tuning the second harmonic tuners, the fundamental source tuner and the load tuner are set at optimum impedance positions derived from the initial sets of measurements. This value slightly changes due to the addition of a diplexer in the setup. After the fundamental source tuner and the load tuner positions were tuned for the maximum output power values, the second harmonic tuner was also tuned to the position that provides the maximum output power. The criteria might be minimum harmonic generation or maximum efficiency or both. Once all tuners are set to the optimum impedance positions, the device should be at its best performance [5].

 When the optimum impedances set by the tuners were known, the input and the output impedance seen by the DUT was derived. It is necessary to characterize each and every device between the input bias and the DUT's gate terminal on the input side and characterize all devices between the DUT's drain terminal and the output bias on the output side. The resulting device impedances are used to embed the impedance seen by the DUT on the input and the output side. This was done using Agilent's Advanced Design Software (ADS) software. The actual setup of the devices and the embedded impedance results are included in Appendix 3, 4 and 5.

 In the case of the test fixture, the fixture was characterized as a whole. Since the DUT was placed in the middle of the fixture, the S-parameter files for the individual halves were needed in order to perform impedance embedding. Assuming that the individual halves of the



fixture were mirror images of each other, the S-parameters for each half of the fixture was calculated. The calculation procedure is included in Appendix 6.

#### 3.2.1 Diplexer Design

When making second harmonic source pull measurements, a diplexer was used on the gate side in order to separate the fundamental frequency from the second harmonic frequency. "A frequency diplexer is a multiport network that takes input composed of several frequencies at one port and produces outputs at other ports with those outputs containing frequencies only in selected frequency bands" [11]. An 8-pole frequency diplexer was designed to enable second harmonic measurements and tuning. The circuit was simulated using ADS. RETMA values were used for the lumped component values. The corresponding circuit is shown in Fig 10. This circuit was later modified to include pads and component parasitcs. The resultant circuit was simulated and the simulated results thus obtained are shown in Fig 11.



Figure 11: Simulation results for diplexer

The diplexer circuit that was designed was then constructed and tested. Fig 12 shows the results that were measured from the diplexer circuit using the network analyzer.





Figure 12: Measured results for diplexer

The measured data from the constructed circuit closely matched the simulation results shown in Fig 11.

#### 3.2.2. Harmonic source pull measurements

When making second harmonic load or source pull measurements, there are two steps. Initially, the source pull was done using the automated tuners by setting the load and fundamental frequency tuner at the optimum impedances and adjusting the second harmonic tuner. The measured results for second harmonic power were recorded corresponding to the second harmonic tuner position. The automated tuners have three different variables that can be changed. These are listed as P1, P2 and L. Changing each of these variables results in the tuner position being moved up or down and back or forth. P1 represents the position with, respect to the line, of a large capacitance slug on the slide screw tuner, P2 represents the position with respect to the line of a smaller capacitive slug and L represents the lateral position of the slug carriage on the line. When measuring the second harmonic power of the device, the tuner position P1 was set at 5000 (completely withdrawn) and P2 was changed to the following values: 20, 250, 500, 1000, 1500, 2000, 2500. For each of these P1, P2 combinations, L was changed from 0 to 21000 and the output second harmonic power was recorded at finite intervals of this L position. The impedances measured at the tuner and the embedded impedances measurements at the DUT corresponding varying P2 and L values are



plotted on Smith Charts and are included in Appendix 7. The plot of L position vs. output second harmonic power is shown in Fig 13 for the condition that  $P1 = 5000$  and  $P2 = 20$ .



Measured Changes in Second Harmonic Power as a Function of Tuner 'L' Position

Tuner Postion (corresponding to different impedances)

Figure 13: Second harmonic output power vs. tuner "L" position

Looking at the plot, the relative second harmonic power varies over a range of 12.9 dB (from 9.7 to -3.2 dBm) when measured as a function of second harmonic input impedance. The second harmonic tuner was characterized using a network analyzer and the impedance corresponding to each of the tuner positions was measured and recorded. Thus, the second harmonic power is known with respect to the impedance at the tuner.

Since the DUT was being characterized, the input and output impedances at the DUT had to be calculated. The impedance found at the tuners was embedded all the way up to the DUT. This was done using ADS as explained in the previous section. The embedded input and output impedances are then used to design the input and output matching networks at the fundamental and second harmonic frequencies. The matching network design technique is explained in the following section. Appendix 8 shows the table with tuner positions,



corresponding impedances at the tuners, the embedded impedances at the DUT and the second harmonic output power that was measured. This constitutes the data that was collected using the source pull measurement technique.

#### 3.2.3. Matching Network Design

 As explained in the earlier sections, the tuners were set to their optimum impedance positions and the corresponding input and output impedances were noted and embedded all the way to the device input and output termination. The matching network is designed corresponding to the embedded input and output impedances. To design the matching network, the  $Q^2+1$  method was used. Fig 14 shows a simple model that can be used for designing the input and output matching networks [11].



Figure 14: Simple matching network model used for input impedance matching

From the embedded impedance measurements, the input and output impedances were at a 2 GHz fundamental frequency as follows:

- Fundamental frequency optimal input impedance:  $19.847 + j3.636$  Ohms
- Second harmonic optimal input impedance:  $7.157 + j 53.478$  Ohms
- Output optimal impedance:  $108.537 j 10.417$  Ohms

For the purposes of this project, the input and output impedances are all matched to  $50 + i0$ Ohms. In the case of the matching network for the fundamental frequency optimal input impedance, the design steps are as follows:

The first step is to get rid of the imaginary part of the impedance. The input impedance is of the form:



 $R + jX$ , where R is the resistance and the X is the reactance. In this case,  $R = 19.847$  Ohms,  $X = 3.636$  Ohms. Reactance can be converted to lumped components as follows:

$$
jX = j\omega L = \frac{1}{j\omega C}
$$

$$
j \cdot 3.636 = j(2\pi)(2e9)(L)
$$

Solving for L,  $L = 0.289344$ nH

Now, only the real part of the impedance needs to be matched to 50 ohms.

The second step in constructing this network would be to find the matching Q of the circuit. The matching Q of the circuit is defined using the ratio of Rp (shunt resistance) and Rs (series resistance). In the case of the fundamental frequency, an input impedance matching circuit was designed and the values for the lumped components were calculated as follows:

$$
Q^{2} + 1 = \frac{Rp}{Rs} = \frac{50}{19.847}
$$
  
\n
$$
Q = 1.23259
$$
  
\n
$$
Q = \frac{\omega L}{R_{s}} = \frac{\omega C}{G_{p}}
$$
  
\n
$$
L = \frac{Q R_{s}}{\omega} = \frac{(1.23259)(19.847)}{2\pi(2e9)} = 1.947e - 9 = 1.947nH
$$
  
\n
$$
C = \frac{Q}{\omega R_{p}} = \frac{1.23259}{2\pi(2e9)(50)} = 1.96173e - 12 = 1.96173pF
$$

The resulting circuit for the fundamental input side looks like the circuit shown in Fig 15.



Figure 15: Input matching network at the fundamental frequency using ideal values



Similarly, in the case of second harmonic frequency, the optimum impedance was found to be  $7.157 + j 53.478$  Ohms. An inductor of  $2.128nH$  was used to get rid of the reactance part of the optimum impedance value. Next the real part of the optimum impedance was matched to 50 Ohms using a  $Q^2+1$  match. The input impedance matching circuit was designed and the values for the lumped components were calculated as follows:

$$
Q^{2} + 1 = \frac{Rp}{Rs} = \frac{50}{7.157}
$$
  
\n
$$
Q = 2.444666
$$
  
\n
$$
L = \frac{QR_{s}}{\omega} = \frac{(2.445)(7.157)}{2\pi(4e9)} = 6.9626e - 10 = 0.69626nH
$$
  
\n
$$
C = \frac{Q}{\omega R_{p}} = \frac{2.445}{2\pi(4e9)(50)} = 1.94567e - 12 = 1.94567pF
$$

The resulting circuit using these ideal values is shown in Fig 16.



Figure 16: Input matching network at the second harmonic frequency using ideal values

In the case of the optimum load impedance, the matching network model that was used was slightly different. This model resembled Fig 17.



Figure 17: Simple matching network model used for load impedance matching



The load impedance was found to be  $108.537 - j 10.417$  ohms. A capacitor of 7.63919pF is used to get rid of the reactance part of the optimum impedance value. Next the real part of the optimum impedance was matched to 50 ohms using a  $Q^2+1$  match. The input impedance matching circuit was designed and the values for the lumped components were calculated as follows:

$$
Q^{2} + 1 = \frac{Rp}{Rs} = \frac{108.537}{50}
$$
  
\n
$$
Q = 1.082
$$
  
\n
$$
L = \frac{QR_{s}}{\omega} = \frac{(1.082)(50)}{2\pi(2e9)} = 4.305e - 10 = 4.305nH
$$
  
\n
$$
C = \frac{Q}{\omega R_{p}} = \frac{1.082}{2\pi(2e9)(108.537)} = 7.93304e - 13 = 0.793304pF
$$

The resulting circuit using these ideal values is shown in Fig 18.



Figure 18: Output matching network at 2GHz using ideal values

The input of the device needed to be connected to a diplexer that separated the fundamental frequency from the second harmonic frequency. The fundamental frequency port of the diplexer was then connected to the circuit designed for the input matching network at the fundamental frequency as shown in Fig 15. The second harmonic port of the diplexer was connected to the circuit designed for the input matching network at the second harmonic frequency as shown in Fig 16. The diplexer design shown in Fig 10 can be used for this purpose. The diplexer consists of 8 lumped components on the fundamental frequency



side and 8 lumped component elements on the second harmonic frequency side. Lumped components do not work well at microwave frequencies due to component parasitics. As the number of circuit elements increase, the more difficult it is to match the simulated results to the measured results obtained from the physical design due to the increased level of complexity of the design. It also makes debugging harder. The solution was to construct a circuit as simple as possible. In this case, the simplest solutions was to construct a circuit that is resonant at the fundamental frequency and place it on the input matching network at the fundamental frequency side so that at the fundamental frequency, the only impedance that the device sees is the impedance that this network was designed for. This same technique is used on the input matching network at the second harmonic frequency. The resonant circuits were designed by first picking appropriate Q values. In this case, a Q value of 10 was chosen. So for circuit that is series resonant at 2 GHz, the inductor and capacitor values were calculated as follows:

For a resonant circuit,

$$
\omega = \frac{1}{\sqrt{LC}}
$$

For a series resonant circuit,

$$
Q = \frac{\omega L_s}{R_s}
$$

Therefore at 2GHz the resonant circuit inductor and capacitor values were,

$$
L_s = \frac{QR_s}{\omega} = \frac{(10)(50)}{(2\pi)(2e9)} = 39.7887 \text{ nH}
$$
  

$$
C_s = \frac{1}{\omega^2 L_s} = \frac{1}{((2\pi)(2e9))^2 (39.7887e - 9)} = 0.159155e - 12 = 0.159155 \text{ pF}
$$

Similarly at 4GHz the resonant circuit inductor and capacitor values were,

$$
L_s = \frac{QR_s}{\omega} = \frac{(10)(50)}{(2\pi)(4e9)} = 19.89 \text{ nH}
$$
  

$$
C_s = \frac{1}{\omega^2 L_s} = \frac{1}{((2\pi)(4e9))^2(19.89e - 9)} = 3.1831e - 13 = 0.079595 \text{ pF}
$$

The resulting input matching networks with the resonant circuit is shown in Fig 19.




Figure 19: Input matching network

The input matching network and the output matching network circuits that are shown in Fig 19 and 18 were then modified to include the pads, parasitics and RETMA values. The parasitic models for the 0402 inductors and capacitors that were used are shown in Appendix 9 and the modified input and output matching networks is shown in Appendix 10.

#### 3.2.4. Simulation Setup and Results for the Matching Network

Proprietary ADS device model of CRF24010 was provided by CREE. This device model was used in obtaining simulation data. The device was connected to the designed matching network at the fundamental frequency and the second harmonic frequency at the input port. The output matching network was connected to the output port. A transient simulation was run in order to look at the nonlinear analysis corresponding to the device. Since the matching networks were themselves derived from the measured S-parameters for the different sections of the load pull setup, it was decided that these measured data would be used to perform the simulations. This decision presented a problem since frequency based Sparameters cannot be used when performing transient simulations. Therefore the Sparameters devices corresponding to the test fixture, the male-to-male connectors, the couplers and the tuners were modeled with transmission line using the de-embedding technique. A diplexer model with microstrip lines that closely matches the measured data



was used for the purposes of the simulation. The overall block diagram of the simulation circuit is shown in Fig 20.



Figure 20: Block diagram of matching network setup

Appendix 11 shows the transmission line model that was used in place of each block. The fundamental source tuner and the load tuner were set at fixed optimum positions and this corresponding optimum impedance was modeled by adjusting the electrical length of the transmission line from the tuner model. The harmonic tuner, on the other hand, must be adjustable so that the second harmonic output power can be looked at as a function of second harmonic input impedance. The structure that was used to model the second harmonic input tuner is shown in Fig 21.



Figure 21: Second harmonic tuner modeled using transmission line

Changing the electrical length, E, of the transmission line shown in Fig 21 simulates the changes of the capacitive slug in tuner position on the actual tuner. Fig 22 shows a circuit that is used to simulate the spectrum analyzer with a second harmonic filter so that the output power at the second harmonic could be noted.





Figure 22: Model of spectrum analyzer using lumped constant elements in ADS

By changing the E of the transmission line over a predetermined range, the output power at 4 GHz can be obtained. The output voltage "HARM" seen on Fig 22 was used to arrive at the second harmonic power for the device. By taking 20 log of the output peak-topeak voltage at HARM, the harmonic output power was obtained. This is not the absolute power, but in this case only the change in simulated second harmonic power compared to the measured second harmonic power was of interest. The electrical length of the transmission line used to model the second harmonic tuner was varied from 10 to 1000 degrees. This corresponds to change in the second harmonic input impedance as set by the tuner. The tuner positions and their corresponding impedances are tabulated and shown in Appendix 12 along with the second harmonic impedances corresponding to electrical length ranging from 10 to 1000 embedded to the input of the DUT and plotted on the Smith Chart.



Simulated Second Harmonic Power as a Function of Electrical Length

Figure 23: Simulation results for second harmonic power vs. electrical length



 As the tuner position changes, the corresponding impedance of the tuner also changes. Looking at this tuner impedance on a Smith Chart, the impedance goes around the chart in a circle. The output power corresponding to these impedances that is shown in Fig 23 ranges from 5.8 to -5.1 dbm. Comapring this to the results found in Fig 13, the trend second harmonic output power trend matches very well. In the case of the measured results, the output power has approximately a 13 dB range (from 9.7 dBm to -3.2dBm) and in the case of the simulated results, the output power varies from 5.8 to -5.1 dBm, which is approximately a 11 dB range. The measured results match very closely to what was simulated.

#### 3.2.5. Measured Results for the Matching Network Circuit

As described in earlier sections, the matching network that was designed for the device was added to the device on the gate and drain ports of the device. A picture of the complete board containing an input impedance match, an output impedance match and the device itself is shown in Appendix 13. The input and output impedances were measured before the boards were assembled together. The results are shown in Table 3.

|                  | <b>Fundamental Impedance</b> |           | <b>Second Harmonic Impedance</b> |           | <b>Output Impedance</b> |           |
|------------------|------------------------------|-----------|----------------------------------|-----------|-------------------------|-----------|
|                  | Real                         | Imaginary | Real                             | Imaginary | Real                    | Imaginary |
| <b>Ideal</b>     | 19.847                       | 3.636     | 7.157                            | 53.478    | 108.537                 | $-10.417$ |
| <b>Simulated</b> | 19.737                       | 1.314     | 7.039                            | 55.108    | 106.154                 | $-8.054$  |
| <b>Measured</b>  | 20.922                       | $-1.249$  | 5.738                            | 42.327    | 98.23                   | $-10.16$  |

Table 3: Ideal, simulated and measured fundamental, second harmonic, and output impedances

 After verifying that the input and output impedances matched the simulated values, the boards were put together and the device was connected to these input and output matching networks. The resulting board was then tested using the same rf power and pulse bias system as the load system but with the spectrum analyzer as the power detector. The results are presented in Table 4.

Table 4: Measured fundamental and second harmonic output power results

|                               | Fundamental<br><b>Output Power</b> | <b>Second Harmonic</b><br><b>Output Power</b> |
|-------------------------------|------------------------------------|---|
| <b>Using Automated Tuners</b> | $32.5$ dBm                         | $9.5$ dBm                                     |
| <b>Using Matching Network</b> | $29.6$ dBm                         | $11.4$ dBm                                    |



Looking at table 14, there is a slight difference between the second harmonic power that was measured using the automated tuners and the second harmonic power that was measured using the designed input and output matching networks. This loss of about 3dB can partially be attributed to higher PCB losses in the system than with the very low loss load pull system.



## CHAPTER 4. SUMMARY AND CONCLUSIONS

The design of nonlinear devices using CAD tools with a nonlinear model of the device has gained importance in recent times, but the accuracy of such models is questionable especially when these CAD tools are used to simulate the nonlinear operation of the device at the fundamental frequency as well as harmonic frequencies under different biasing conditions [12]. Experimental measurements provide accurate data about the nonlinear device. Most experimental techniques used to design power amplifiers only take the fundamental frequency into account while ignoring the harmonic effects. When design constraints are stringent in terms of output power and efficiency, harmonic effects need to taken into account by the designer if the specifications are to be met. The load pull system is an important measurement technique used in making large signal nonlinear device operation measurements both at the fundamental frequency as well as the harmonic frequencies under different biasing conditions [12].

Power MESFET devices like the one tested can be used to design power amplifiers with the measurements that are already collected. By finding the input and output impedances that would result in the best device circuit performance as well as maximum or minimum second harmonic effects, high efficiency power amplifiers can be designed. These types of power amplifiers can be used in communication circuits, especially as part of the transmitter circuit. The power amplifier is the largest source of distortion in wireless communication circuits. Therefore it is very important to design the power amplifier for best performance [13]. This can be done by characterizing the device itself at both fundamental as well as harmonic frequencies. In this research project the second harmonic effects are studied and the circuit performance is optimized by controlling the second harmonic input impedance.

 For the purposes of this research project, the load pull system is used make second harmonic measurement in order to examine the second harmonic effects on the output power of a SiC power MESFET device (CREE CRF24010) at 2 GHz and a Vds of 25V, Ids of 530mA under a pulsed rf and pulsed bias condition with a 1% duty cycle. The second harmonic input impedance was varied using automated tuners and the corresponding output power at the second harmonic frequency (4 GHz) was measured. Depending on the second



harmonic input impedance, the output power varied from 9.5 dBm to 11.4 dBm. In this case, the measured data was used to design input and output matching network circuits on PCB that would provide the maximum second harmonic output power. The matching network circuits were then connected to the DUT and it was verified that the DUT still provided the same output power at the fundamental and second harmonic frequencies as when the measurements were made with the automated tuner. This means that the matching networks that were designed could be utilized whenever the DUT is used in a circuit that requires the best performance from the DUT. So by just adding the matching networks to the input and output of the DUT, the device has been made efficient and thus the circuit that the DUT is used in will only see the best performance from the DUT.



# APPENDIX 1: PICTURE OF THE LOAD PULL SETUP



$$
\text{Max}(\mathbf{z}_\text{in}(\mathbf{z}_\text{out}(\mathbf{z}_\text{out}))
$$

## APPENDIX 2. LOAD PULL RESULTS FOR SiC MESFET DEVICE AT 2.0GHz USING SNPW PROGRAM



Fixed Load Pull  $Freq = 2.0000 GHz$ ZSource (Ohms):  $2.33 + j 2.78$ 

 $max = 31.92$  dBm Pout at  $3.58 + j 7.21$  Ohms 10 contours, 2.00 dBm step  $(12.00 \text{ to } 30.00 \text{ dBm})$ Gt  $max = 19.04 dB$ at  $3.58 + j 7.21$  Ohms 10 contours, 2.00 dB step  $(0.00 \text{ to } 18.00 \text{ dB})$ Eff  $max = 11.12$   $\approx$ at  $3.58 + j 7.21$  Ohms 10 contours, 1.50 % step  $(-3.00 \text{ to } 10.50 \text{$ }) Specs: OFF

#### Zload (Ohms) @ 3.79 + j 6.37





# APPENDIX 3. EMBEDDING FUNDAMENTAL INPUT IMPEDANCE TO THE GATE OF THE DUT



$$
\lim_{t\to 0}\lim_{t\to 0}\frac{1}{t}\prod_{i=1}^n
$$



## APPENDIX 4. EMBEDDING SECOND HARMONIC INPUT IMPEDANCE TO THE GATE OF THE DUT



## APPENDIX 5. EMBEDDING OUTPUT IMPEDANCE TO THE DRAIN OF THE DUT







## APPENDIX 6. TEST FIXTURE S-PARAMETER CALCULATIONS

When making s-parameter measurements on the test fixture, the measurements were made for the fixture as a whole. Since the Maury SNP program requires that the s-parameter on port 1 of the DUT be input as one file and the s-parameter on port 2 of the DUT be input as another file, the s-parameter for each half of the DUT needs to be derived from the complete fixture s-parameter file that was measured.

The two halves of the fixture are to be called Part A and Part B from now onwards. Fig 24 shows the two parts of the fixture whose s-parameters are to be measured. Part A and part B of the fixture are assumed to be symmetrical. So the assumption that port 2 of part A and port 2 of part B are the same is made.



Figure 24: Test fixture setup

The s-parameter of the whole fixture is known from the measured results and the sparameters of part A and part B is to be derived from the measured s-parameter file of the whole fixture. Fig 25 gives an overview of the process used to perform this derivation. The sparameter of the whole fixture is converted to T-parameters. From this, the corresponding Tparameters from part A and part B is calculated. Once the T-parameters have been obtained, they are once again converted back to s-parameters for part A and part B. This is the overall process.





Figure 25: Overview of the derivation process

The first step in finding the s-parameters for each part is to convert the s-parameter for the whole fixture to T-parameters. This is done using the Gonzalez method as shown in (27) [11].

$$
(T)|_G = \begin{pmatrix} \frac{1}{S_{21}} & -\frac{S_{22}}{S_{21}} \\ \frac{S_{11}}{S_{21}} & -\frac{\Delta s}{S_{21}} \end{pmatrix}
$$
 (27)

Since, from an earlier assumption, it is known that part A is symmetrical to part B, the Tparameters for these two parts are as follows:

T-parameter for part A = 
$$
\begin{pmatrix} T_{11} & T_{12} \\ T_{21} & T_{22} \end{pmatrix}
$$
 (28)

T-parameter for part  $B =$  $T_{12}$   $T_{22}$   $\int \Delta T$  $T_{11}$   $-T_{1}$  $\frac{1}{\Delta}$ J  $\setminus$  $\overline{\phantom{a}}$  $\setminus$ ſ −  $-\frac{T_{21}}{T_{21}}$   $\frac{1}{T_{21}}$  $12 \t 22$  $\frac{11}{T}$   $\frac{1}{T}$  (29)

The T-parameters for the whole fixture is assumed to be as follows:

$$
T_{total} = \begin{pmatrix} G_{11} & G_{12} \\ G_{21} & G_{22} \end{pmatrix} \tag{30}
$$

The product of the T-parameters from part A and part B results in the T-parameter for the whole fixture. This is shown using Eqns 31 and 32.

$$
\begin{pmatrix} T_{11} & T_{12} \\ T_{21} & T_{22} \end{pmatrix} \begin{pmatrix} T_{11} & -T_{21} \\ -T_{12} & T_{22} \end{pmatrix} \frac{1}{\Delta T} = T_{total}
$$
\n(31)



42

$$
\frac{1}{\Delta T} \left( \frac{T_{11}^{2} - T_{12}^{2}}{T_{11} T_{21} - T_{12} T_{22}} - \frac{T_{11} T_{21} + T_{12} T_{22}}{T_{22}^{2} - T_{21}^{2}} \right) = T_{total} = \left( \frac{G_{11}}{G_{21}} - \frac{G_{12}}{G_{22}} \right)
$$
\n(32)

Since 
$$
\Delta T = T_{11}T_{22} - T_{12}T_{21} = 1 + j0
$$
 and  $G_{21} = -G_{12}$ ,

$$
T_{11}^2 - T_{12}^2 = G_{11} \tag{33}
$$

$$
-T_{11}T_{12} + T_{12}T_{22} = G_{12}
$$
\n(34)

$$
T_{11}T_{12} - T_{12}T_{22} = -G_{12}
$$
 (35)

$$
T_{22}^2 - T_{12}^2 = G_{22}
$$
 (36)

Since 
$$
\Delta T = 1
$$
, we also know that

$$
T_{11}T_{22} + T_{12}^2 = 1\tag{37}
$$

$$
1 - T_{11}T_{22} = T_{12}^2 \tag{38}
$$

From (35),

$$
T_{12} = -G_{12} / (T_{11} - T_{22})
$$
 (39)

$$
(33) - (36)
$$
 results in (40):

$$
T_{11}^2 - T_{22}^2 = G_{11} - G_{22} = (T_{11} - T_{22})(T_{11} + T_{22})
$$
\n(40)

$$
(33) + (36) results in (41):
$$

$$
T_{11}^2 - 2 T_{12}^2 + T_{22}^2 = G_{11} + G_{22}
$$
\n(41)

$$
T_{11}^2 - 2(1 - T_{11}T_{22}) + T_{22}^2 = G_{11} + G_{22}
$$
\n(42)

$$
T_{11}^2 + 2T_{11}T_{22} + T_{22}^2 - 2 = G_{11} + G_{22}
$$
\n(43)

$$
(T_{11} + T_{22})^2 = G_{11} + G_{22} + 2 \tag{44}
$$

From the previous simplifications,

$$
(T_{11} + T_{22})^2 = G_{11} + G_{22} + 2 \tag{45}
$$

$$
T_{11}^2 - T_{22}^2 = G_{11} - G_{22}
$$
 (46)

If,

$$
A = T_{11} + T_{22} \tag{47}
$$

$$
\mathbf{B} = \mathbf{T}_{11} - \mathbf{T}_{22} \tag{48}
$$

Then,

$$
A^2 = G_{11} + G_{22} + 2 \tag{49}
$$

$$
AB = G_{11} - G_{22} \tag{50}
$$

$$
A = \pm \sqrt{G_{11} + G_{22} + 2} = T_{11} + T_{22}
$$
\n(51)



$$
B = \pm \frac{G_{11} - G_{22}}{\sqrt{G_{11} + G_{22} + 2}} = T_{11} - T_{22}
$$
\n(52)

$$
T_{11} = \frac{A+B}{2}
$$
 (53)

$$
T_{22} = \frac{A - B}{2} \tag{54}
$$

$$
T_{12} = -\frac{G_{12}}{B} \tag{55}
$$

$$
T_{21} = -T_{12} = \frac{G_{12}}{B} \tag{56}
$$

$$
(S_A) = \begin{pmatrix} \frac{T_{21}}{T_{11}} & \frac{\Delta T}{T_{11}} \\ \frac{1}{T_{11}} & -\frac{T_{12}}{T_{11}} \end{pmatrix}
$$
 (57)

$$
(S_B) = \begin{pmatrix} \frac{T_{21}}{T_{11}} & -\frac{1}{T_{11}} \\ -\frac{1}{T_{11}\Delta T} & -\frac{T_{12}}{T_{11}} \end{pmatrix}
$$
 (58)

$$
\lim_{z\to z\to z} \mathbf{K} \log z
$$

#### APPENDIX 7: INPUT IMPEDANCE AT THE TUNER AND DUT PLOTTED ON A SMITH CHART

The impedance circles shown in this appendix contain both blue and red impedance circles. The red circle corresponds to the impedance at the tuner and the blue circle corresponds to the impedance at the DUT (after embedding is completed). On the smith chart, m1 and m3 correspond to the impedance that provides the maximum second harmonic output power and m2 and m4 correspond to the impedance that provides the minimum second harmonic output power.



At tuner positions:  $P1 = 5000$ ,  $P2 = 20$ :



At tuner positions:  $P1 = 5000$ ,  $P2 = 250$ :



At tuner positions:  $P1 = 5000$ ,  $P2 = 500$ :





At tuner positions:  $P1 = 5000$ ,  $P2 = 1000$ :



At tuner positions:  $P1 = 5000$ ,  $P2 = 1500$ :



$$
\lim_{t\to 0}\lim_{n\to\infty}\frac{1}{n}\int_{\mathbb{R}^n}\left|\frac{d\mathbf{x}}{dx}\right|^{n-1}dx
$$













$$
\lim_{\omega\rightarrow\infty}\mathbf{Z}=\mathbf{I}
$$



$$
\lim_{\omega\rightarrow\infty}\mathbf{Z}=\mathbf{I}
$$





















## APPENDIX 9. PARASITIC MODELS FOR 0402 INDUCTORS AND CAPACITORS



Inductor parasitic model for 0402 parts







## APPENDIX 10: INPUT AND OUTPUT MATCHING CIRCUIT SCHEMATIC



#### APPENDIX 11: TRANSMISSION LINE APPROXIMATION FOR EACH IMPEDANCE BLOCK USED IN THE SECOND HARMONIC SOURCE PULL SETUP

Fundamental Tuner



## 2<sup>nd</sup> Harmonic Tuner



## **Diplexer**



Male to Male connector





Input Coupler



Input Half of Test Fixture



### Output Half of Test Fixture







www.manaraa.com

#### APPENDIX 12: SIMULATED SECOND HARMONIC INPUT IMPEDANCES AND OUTPUT POWER CORRESPONDING TO ELECTRICAL LENGTH OF THE TRANSMISSION LINE USED TO MODEL THE TUNER









## APPENDIX 13: PICTURE OF THE BOARD WITH THE MATCHING INPUT AND OUTPUT IMPEDANCES ON THE DEVICE



$$
\lim_{\omega\rightarrow\infty}\mathbf{Z}=\mathbf{I}
$$

## **BIBLIOGRAPHY**

[1] Maury Microwave Corporation, "Theory of Load and Source Pull Measurement," [Online application notes], (1999 Jul 27), Available at HTTP: http://maurymw.com/support/pdfs/5C-041.pdf

[2] D. C. Yang and D. F. Peterson, "Large-Signal Characterization of Two-Port Nonlinear Active Networks," Transactions on Microwave Theory and Techniques, vol. 30, no. 12, Dec. 1982, pp. 345-347.

[3] J. Sevic, "Introduction to Tuner-Based Measurement and Characterization," [Online technical data], (2004 Aug 31), Available at HTTP:

http://www.maurymw.com/support/pdfs/5C-054.pdf

[4] CREE, "CRF24010," [Online datasheet], (2007 Aug), Available at HTTP:

http://www.cree.com/products/pdf/CRF24010-Rev1\_8.pdf

[5] Maury Microwave Corporation, "Device Characterization with Harmonic Source and Load Pull," [Online application notes], (2000 Dec 7), Available at HTTP:

http://www.maurymw.com/support/pdfs/5C-044.pdf

[6] G. R. Simpson and M. Vasser, "Importance of  $2^{nd}$  Harmonic Tuning for Power Amplifier Design," 48<sup>th</sup> ARFTG Conference Digest, vol. 30, Dec. 1996, pp. 1-6.

[7] "Automated Tuner System -MT980 Series: Operating and Service Manual," Ontario, CA: Maury Microwave Corporation, 1995.

[8] S. V. Sekar, H. Cao, and R. J. Weber, "Changes in dc Current Bias as a Function of Input Drive for a Depletion Mode SiC MESFET," presented at IEEE International Conference on Electro/Information Technology. Ames, IA, 2008.

[9] W. R. Curtice, "A MESFET Model for Use in the Design of GaAs Integrated Circuits," IEEE Transactions on Microwave Theory and Techniques, vol. 28, May 1980, pp. 448-456. [10] R. Ludwig, and P. Bretchko, RF Circuit Theory and Applications, Pearson Education, Inc., 2000, pp. 331-340

[11] R. J. Weber, "Introduction to Microwave Circuits," Piscataway: IEEE Press, 2001 [12] P. Berini, M. Desgagne, F. M. Ghannouchi, and R. G. Basisio, "An Experimental Study of the Effects of Harmonic Loading on Microwave MESFETS Oscillators and Amplifiers," Transactions on Microwave Theory and Techniques, vol. 42, no. 6, Jun. 1994, pp. 943-950.


[13] R. K. Varanasi, C. P. Baylis II, L. P. Dunleavy and Harris Corporation, "Prediction of Harmonic Tuning Performance in p-HEMTs," The 2005 IEEE Annual Conference on Wireless and Microwave Technology, 2005 pp. 183-186.



## ACKNOWLEDGEMENTS

This degree would not be possible without the help and guidance of my major professor, Dr. Robert Weber. I would like to thank him for helping me learn immensely in the last few semesters. Working in your lab has allowed me to acquire a great number of skills as an rf engineer. You are a professor I greatly respect and admire. Thank you for everything.

I would like to thank my dad, Dr. Vaithilingam Sekar, and mom, Ms. Birundha Sekar for being the biggest and best influences of my life. You have opened up so many opportunities for me. I owe all my current and future success to both of you. Without you guys, none of this would be possible. Thank you for all that you have done for me. I will always be grateful.

I would like to thank my sister Dr. Poorani Sekar for always believing the best in me. You have been my biggest supporter and well wisher. You set the standards in the family and pushed me to do my best. I am proud to be your sister.

I would also like to thank my peers for all their help in the lab. Bruce, I have always enjoyed our discussions about research. Your different point of view has provided me with a few insights that have led me to solve problems with research. Harry, I would like to thank you for answering all of my questions about the load pull setup. I would also like to thank Jin-Wei and Sanyi for their help milling boards even amidst their busy schedules. I not only consider all of you my peers, but also my friends. I would also like to thank Dr. Atiwat Aimdilokwong for documenting his initial work with the load pull system. The documentation that he provided helped immensely in getting started with the measurements.

And finally, I would like to extend a special thanks to my friend Jacob Sloat. Thank you for your help in making the boards. Thank you for giving me rides home late at night. Thank you for your continued support. You have always been there for me. The last few months would have been a lot more difficult if it had not been for your help. I appreciate all that you have done.

